Pinning by planar defects and the planar glass phase*

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- 1. Bragg glass : A reminder
- 2. Planar defects
- 3. A single planar defect
- 4. Many defects
- 5. Relation to other problems

Bragg Glass -A Reminder

<u>Bragg glass: a reminder</u>



Elastic constants c_{11} , c_{44} , c_{66} remain finite!

$$\mathcal{H}_{\mathsf{el}} = \frac{1}{2} \int d^2 x dz \left\{ c_{11} (\boldsymbol{\nabla}_{\perp} \mathbf{u})^2 + c_{66} (\boldsymbol{\nabla}_{\perp} \times \mathbf{u})^2 + c_{44} (\boldsymbol{\nabla}_{\parallel} \mathbf{u})^2 \right\}$$

Sample to sample fluctuations of free energy



<u>non-linear resistivity</u> $\rho(j) \sim \exp -[j(H,T)/j]^{\mu}$

Bragg glass $\chi=1$, $\mu=\chi/(2-\zeta)=1/2$

Vortex phase diagram, elastic theory



Planar Defects



Cut



Weld









Letters to Nature

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Critical currents approaching the depairing limit at a twin boundary in YBa₂Cu₃O₇₋ _{Ivan Maggio-Aprile¹}, Christophe Renner¹, Andreas Erb¹, Eric Walker¹ and Øystein Fischer¹



The grey scale is defined by the ratio of the conductance measured at 20 meV to the conductance measured at zero bias. Grey tones varying from clear to dark correspond to ratios ranging from high to low. Note that for experimental reasons, the centre of the different images presented here are not exactly at the same position; this puts the twin boundary (TB) at slightly different positions relative to the centre in the various images. **a**, 170 170 nm² image taken at 3 T (field-cooled). Both domains are filled with a nearly equal density of flux lines, and the 90° rotation of the *ab* -plane anisotropy is observed across the TB. **b**, 150 150 nm² image taken 12 hours after the field was reduced from 3 to 1.5 T. The arrows indicate the vortex movements observed in the domain to the right, forming non-continuous lines extending in a direction parallel to the TB. **c**, Three days after field reduction, no more flux lines can be detected throughout the domain to the right over at least 80 nm. **d**, 150 150 nm² image taken at 3 T–1.5 T–0 T–6 T field cycle. Both domains show a high density of flux lines, and a flux gradient is measured across the TB. **e**, Topographic image of the YBCO surface taken simultaneously with **d**. The TB appears as a narrow structure about 0.1 nm deep. Note that the width of this line is much smaller than the width of the dark line in the spectroscopic images, giving further support to the interpretation that the dark line comes from a high density of vortices along the TB.



Planar defects in BSCCO (M. Menghini, Y. Fasano, F. De la Cruz, and E. Zeldov)

- twin boundaries in YBCO crystals - width \sim 2nm distance, \sim 1 μ m





These images were taken by Martín Irigoyen under the direction of Eduardo Rodríguez1

 TEM micrography showing the presence of twin boundaries in the YBCO melt-textured samples. [sample by IFW, Dresden; image by CNRSM-PASTIS]



A Single Planar Defect

Parametrization of the defect plane



Position vector on the defect plane $\mathbf{r}_D = (\mathbf{x}_D, z_D) + \Delta \mathbf{n}_D, \quad z_D = t \cos \beta,$ $\mathbf{x}_D = (s \sin \alpha - t \cos \alpha \sin \beta, s \cos \alpha + t \sin \alpha \sin \beta)$

14

Defect planes Hamiltonian



$$\rho_{\text{vortex}}(\mathbf{u},\mathbf{r}) \approx \frac{1}{a_B^2} \frac{1}{|1 + \partial_{\alpha} u_{\alpha}|} \sum_{\mathbf{G}} e^{i\mathbf{G} \left(\mathbf{x} - \mathbf{u}(\mathbf{r})\right)}$$
vortex density
$$\underline{\text{Defect energy}}$$

$$H_{\text{D}} = \int d^3 \mathbf{r} \ V_{\text{D}}(\mathbf{r}) \ \rho(\mathbf{r})$$

Defect potential $V_{\underline{D}}(\mathbf{r}) \approx -\mathbf{v} \ \delta(\mathbf{r}-\mathbf{r}_{D})$

$$\mathcal{H}_{D} = v\rho_{0} \int dt ds \left\{ \nabla_{\mathbf{x}} \mathbf{u}(\mathbf{r}_{D}) - \sum_{\mathbf{G}\neq\mathbf{0}} e^{i\mathbf{G}[\Delta\mathbf{n}_{D} + \mathbf{x}_{D} - \mathbf{u}(\mathbf{r}_{D})]} \right\}$$

Is a defect a relevant perturbation?

$$\boldsymbol{\boldsymbol{\boldsymbol{\mathcal{H}}}}_{D} = \boldsymbol{\boldsymbol{\boldsymbol{\nu}}} \rho_{0} \int dt ds \left\{ \boldsymbol{\nabla}_{\mathbf{x}} \mathbf{u}(\mathbf{r}_{D}) - \sum_{\mathbf{G} \neq \mathbf{0}} e^{i\mathbf{G}[\boldsymbol{\boldsymbol{\mathcal{X}}} \mathbf{n}_{D} + \mathbf{x}_{D} - \mathbf{u}(\mathbf{r}_{D})]} \right\} \boldsymbol{\boldsymbol{\boldsymbol{\mathcal{Y}}}} \boldsymbol{\boldsymbol{\boldsymbol{\mathcal{L}}}} \boldsymbol{\boldsymbol{\mathcal{H}}}$$



exp {Gx_D(s,t)}= 1 → defect plane <u>paralle</u>l B

Gx_D(s,t)= 0 defect plane characterized by (integer) Miller indices

 δ : distance between equivalent defect planes

D>~ v cos(2π
$$\Delta/\delta$$
) (L/L_a)^{2-g}

$$(3/8)$$
 η_G a^2/δ^2 ψ - χ =1-g > 0

Thus defect relevant if $g \le 1$ and

 $G=mb_1+nb_2$

$$L > L_{\rm D} \equiv L_{\rm a} (ca^2 L_{\rm a} / v)^{1/(1-g)}$$

$$g \equiv (3/8) \eta_6 a^2/\delta^2$$

 $1.14 < \eta_6 < 1.16$
 $a^2/\delta^2 = 4/3(m^2 + mn + n^2)$
m, n Miller indices of
defect plane

 $g = \eta_{G}/2, \ 3\eta_{G}/2, \ 7\eta_{G}/2, \dots, < 1!$



Weak tilted defects always irrelevant 17

So far: weak defects Now: <u>Critical coupling for strong defects?</u>

Integrate out all displacements out of defect plane \Rightarrow effective model for $\varphi = 2\pi u_D(r_D)/\delta$

$$\mathcal{H}_{2\mathrm{D}} = \frac{K}{2} \int d^2 \mathbf{q} |\mathbf{q}| |\varphi_{\mathbf{q}}|^2 + \int d^2 r_D \left\{ \frac{2\sqrt{\pi g}K}{\xi} \cos(\varphi - \alpha) + \frac{v_1}{L_a^2} \cos(\varphi) \right\}$$



<u>Density oscillations close to the defect</u>



If defect not parallel B: additional factor e^{-x/x_B} , $x_B = 1/(G_D |sin \beta|)$



Defect planes of random distance



Relevance of many defects (no point disorder)

Ignore displacement parallel to defects:

dimensionality shift D -2



D=3: exponential decay of correlations in direction perpendicular to defects



upper critical dimension D=6

Functional renormalization group calculation in D=6- ϵ

Elastic constants $c_{44}, c_{66} \rightarrow \infty$





without defects

with defects

 $\theta \ll 1$

$$\frac{\Delta E}{L_x L_y} = \frac{c_{44}}{2} L_z \theta^2 \qquad \qquad \frac{\Delta E}{L_x L_y} \approx \Sigma_z \theta$$



Transverse Meissner effect $H_{x,c} \sim \Sigma_z \delta / \phi_0$ Resistance agains shear strees $\sigma_{xy,c} \sim \Sigma_y \delta$

Diverging sample to sample fluctuation of magnetic susceptibility

- longitudinal susceptibility $\chi = \rho_0 \phi_0 \frac{\langle \partial_x u_x \rangle}{\partial H_z}$ $\overline{\chi} = \frac{(\rho_0 \phi_0)^2}{4\pi c_{11}}$ No dependence on disorder due to statistical tilt symmetry.
- Perturbation theory gives $(\overline{\chi^2} - \overline{\chi}^2)/\overline{\chi}^2 = R_D^{\prime\prime\prime\prime}(0)L^{\epsilon}/(5c_{11}^2) \sim (L/L_D)^{\epsilon}$, for $L < L_D$. Signature of a glassy phase!



 $\mathsf{E}_{\mathsf{drop}} = \mathsf{L}_{\mathsf{x}} \mathsf{L}_{\mathsf{y}} \mathsf{L}_{\mathsf{z}} \left(\mathsf{c}_{11} \delta^2 / \mathsf{L}_{\mathsf{x}}^2 + \Sigma_{\mathsf{z}} / \mathsf{L}_{\mathsf{z}} + \Sigma_{\mathsf{y}} / \mathsf{L}_{\mathsf{y}} - \mathsf{f} \delta \right)$



<u>Relevance of many defects in the presence</u> <u>of point disorder</u>

Assume defects of random distance but identical orientation



<u>non-linear resistivity</u> $\rho(j) \sim \exp -[j(H,T)/j]^{\mu}$



Transverse displacements: dislocations



Relations to other problems

Closely related problems:



G = 0

0

Superconducting plane with line defect

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Non-Hermitian Luttinger liquids and vortex physics

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1-d electron liquid (Luttinger liquid) with point defect(s) $G = \frac{e^2}{h} \frac{4t^2}{(1+t^2)^2}$ NUMBER 8 PHYSICAL REVIEW LETTERS 24 FEBRUARY 1992 **Transport in a One-Channel Luttinger Liquid** C. L. Kane d=1+1 Department of Physics, University of Pennsylvania, Philadelphia, Pennsylvania 19104 $G = \frac{e^2}{b}g$ Matthew P. A. Fisher IBM Research, T. J. Watson Research Center, P.O. Box 218, Yorktown Heights, New York 10598 g conductance (Received 15 November 1991) We study theoretically the transport of a one-channel Luttinger liquid through a weak link. For repulsive electron interactions, the electrons are completely reflected by even the smallest scatterer, leadq ing to a truly insulating weak link, in striking contrast to that for noninteracting electrons. At finite temperature (T) the conductance is nonzero, and is predicted to vanish as a power of T. At T=0power-law current-voltage characteristics are predicted. For attractive interactions, a Luttinger liquid is argued to be perfectly transmitted through even the largest of barriers. The role of Fermi-liquid leads is also explored.

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with defect(s)

- Single defect relevant if g < 1 for all defect strength
- Many defects relevant if g < 3/2
- Density (Friedel) oscillations close to the defect with power g and 2g-1 for relevant and irrelevant defects, respectively.
- Coupling constant g tunable

Summary

- The Bragg glass phase shows quasi-LRO with non-universal decay exponent $\eta_{\text{BG}}(c_{66}/c_{11}).$
- Single planar defect in the Bragg glass phase is a relevant perturbation provided the defect is parallel to B and
- g=(3/8) η_G(a/δ)² <1.
- Close to the defect the vortex density shows Friedel like density oscillations with decay exponent g<1.
- Randomly arranged weak defects become relevant in D<6 dimensions. In D=3 and in the presence of point disorder defects are relevant for g<3/2.
- Planar defects lead to a transverse Meissner effect and a threshold against shear deformation.
- The creep exponent is $\mu = 3/2$.